

**• General Description**

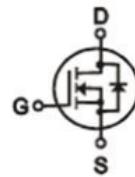
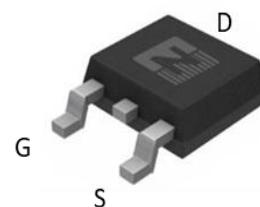
The ZMS070N10D combines advanced trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$.

• Features

- Low $R_{DS(ON)}$ to minimize conductive loss
- Low Gate Charge for fast switching
- Low Thermal resistance

• Application

- SMPS 2nd Synchronous Rectifier
- Load switch
- BLDC Motor driver

• Product Summary $V_{DS} = 100V$ $R_{DS(ON)} = 7m\Omega$ $I_D = 75A$ 

TO-252

• Ordering Information:

Part NO.	ZMS070N10D
Marking	ZMS070N10
Packing Information	REEL TAPE
Basic ordering unit (pcs)	2500

• Absolute Maximum Ratings ($T_C = 25^\circ C$)

Parameter	Symbol	Conditions	Rating	Unit
Drain-Source Voltage	V_{DS}	$25^\circ C \leq T_j \leq 175^\circ C$	100	V
Gate-Source Voltage	V_{GS}	Pulsed ^①	+20/-20	V
Continuous Drain Current	I_D	$T_C=25^\circ C$	75	A
	I_D	$T_C=75^\circ C$	54	A
	I_D	$T_C=100^\circ C$	38	A
Pulsed Drain Current	I_{DM}	pulsed; $t_p \leq 10 \mu s$; $T_{mb} = 25^\circ C$	225	A
Total Power Dissipation	P_D	$T_C=25^\circ C$	71	W
Total Power Dissipation	P_D	$T_A=25^\circ C$	3.0	W
Operating Junction Temperature	T_J		-55 to 175	°C
Storage Temperature	T_{STG}		-55 to 175	°C
Single Pulse Avalanche Energy	E_{AS}	$L=0.1mH$, $V_{GS}=10V$, $R_g=25\Omega$, $T_J=25^\circ C$	120	mJ
ESD Level (HBM)			Class 1C	

**•Thermal resistance**

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case	R _{thJC}	-	-	2.1	° C/W
Thermal resistance, junction - ambient	R _{thJA}	-	-	50	° C/W
Soldering temperature	T _{sold}	-	-	260	° C

•Electronic Characteristics

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} = 0V, I _D = 250μA	100			V
Gate Threshold Voltage	V _{GS(TH)}	V _{GS} = V _{DS} , I _D = 250μA	1.2		2.5	V
Drain-Source Leakage Current	I _{DSS}	V _{DS} =100V, V _{GS} = 0V			1.0	uA
Gate- Source Leakage Current	I _{GSS}	V _{GS} =±20V, V _{DS} = 0V			±100	nA
Static Drain-source On Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =30A		7	9	mΩ
		V _{GS} =4.5V, I _D =20A ^③		9	11	mΩ
Forward Transconductance	g _{FS}	V _{DS} = 25V, I _D =10A		16		s
Diode Forward Voltage	V _{FSD}	I _S =30A			1.2	V

•Dynamic Characteristics

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Input capacitance	C _{iss}	f = 1MHz, V _{DS} =25V	-	2190	-	pF
Output capacitance	C _{oss}		-	1130	-	
Reverse transfer capacitance	C _{rss}		-	138	-	
Gate Resistance	R _g	f = 1MHz		1.6		Ω
Total gate charge	Q _g	V _{DD} = 15V I _D = 5A V _{GS} = 10V	-	33	-	nC
	Q _{g(4.5v)}			16		
Gate - Source charge	Q _{gs}		-	6.8	-	
Gate - Drain charge	Q _{gd}		-	5.8	-	
Turn-ON Delay time	t _{D(on)}	V _{GS} =10V, V _{DS} =15V R _G = 6Ω, I _D = 15A		14		ns
Turn-ON Rise time	t _r			21		ns
Turn-Off Delay time	t _{D(off)}			28		ns
Turn-Off Fall time	t _f			7		ns
Reverse Recovery Time	t _{RR}	V _{DD} = 20 V, dI _S /dt = 100 A/s, I _S = 30 A		56		ns
Reverse Recovery Charge	Q _{RR}			67		nC



Fig.1 Gate-Charge Characteristics

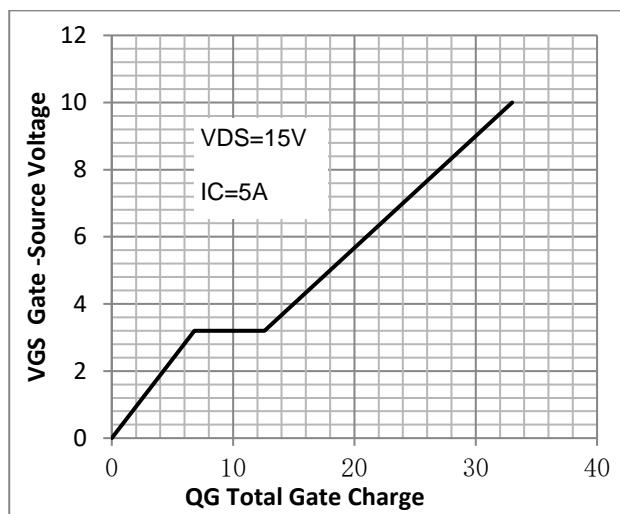


Fig.2 Capacitance Characteristics

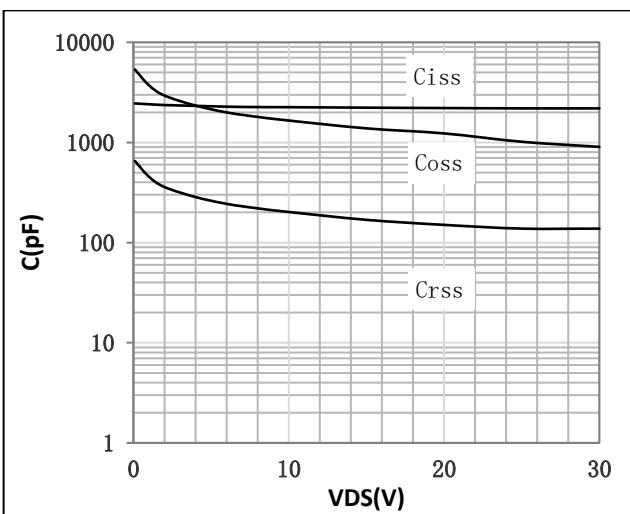


Fig.3 Power Dissipation

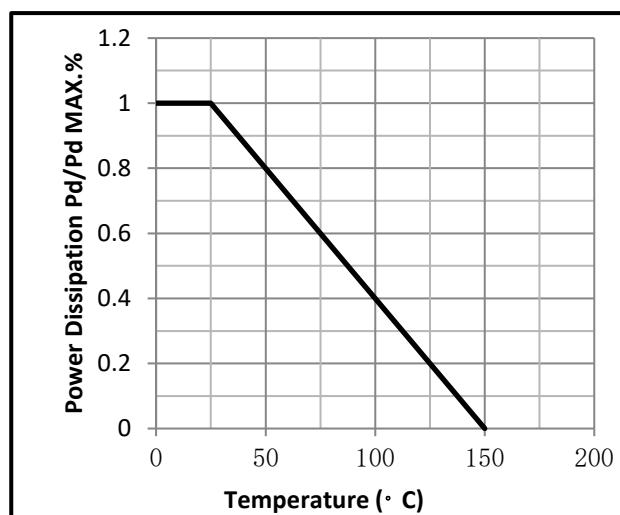


Fig.4 Typical output Characteristics

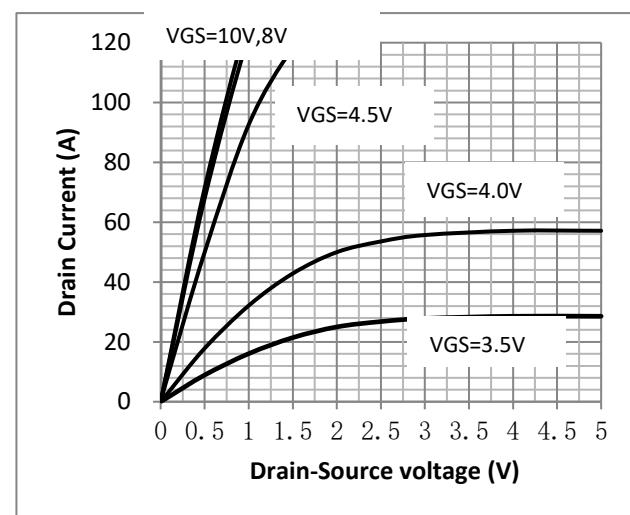


Fig.5 Threshold Voltage V.S Junction Temperature

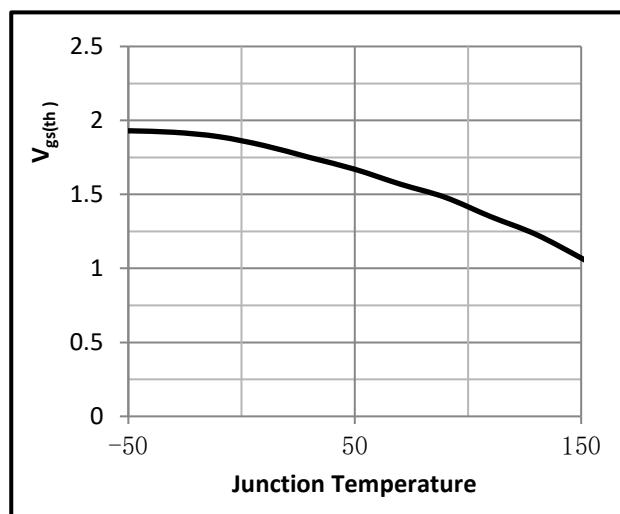


Fig.6 Resistance V.S Drain Current

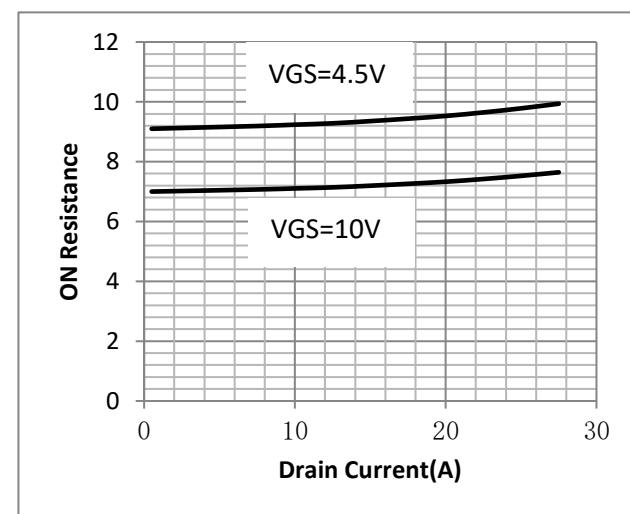




Fig.7 On-Resistance VS Gate Source Voltage

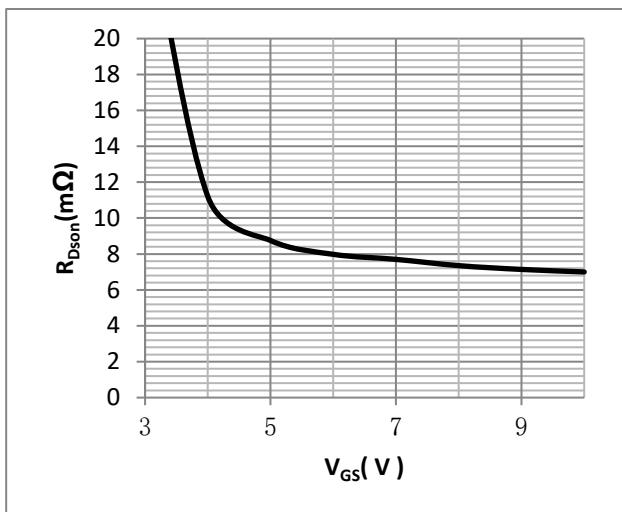


Fig.8 On-Resistance V.S Junction Temperature

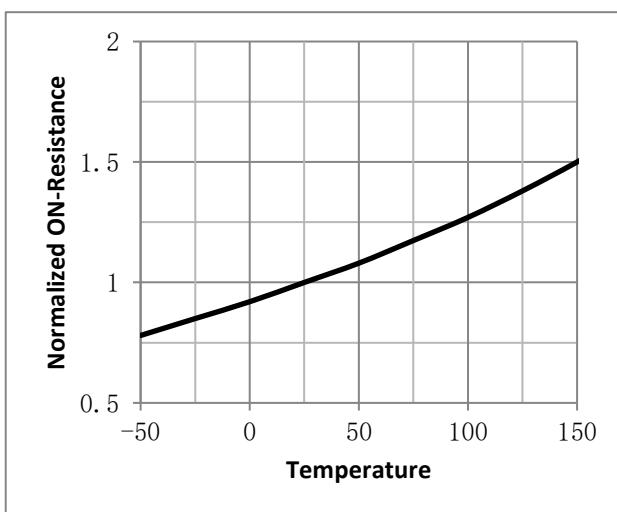


Fig.9 Diode Forward Voltage vs. Current

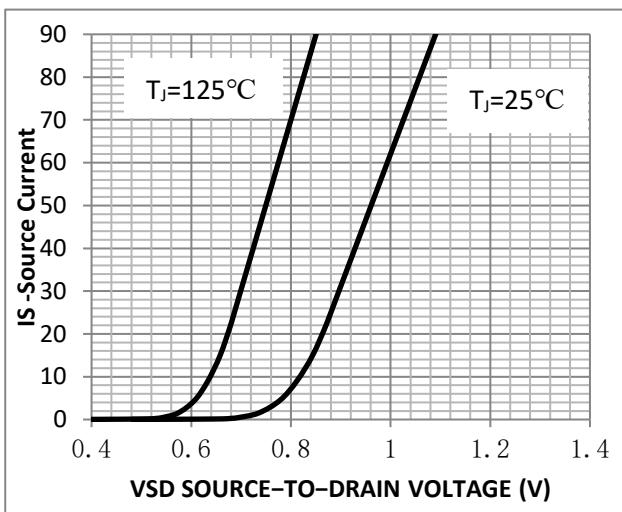


Figure.10 Transfer Characteristics

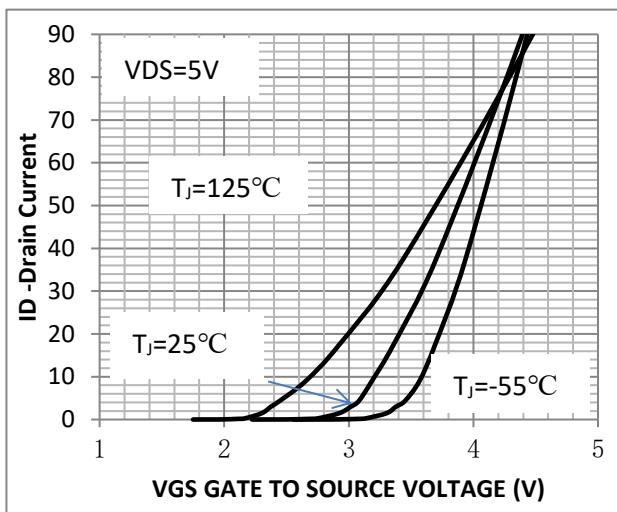


Fig.11 SOA Maximum Safe Operating Area

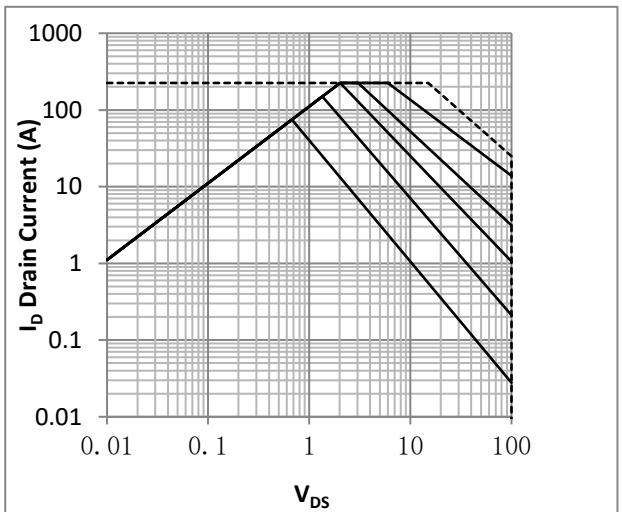


Fig.12 ID-Junction Temperature

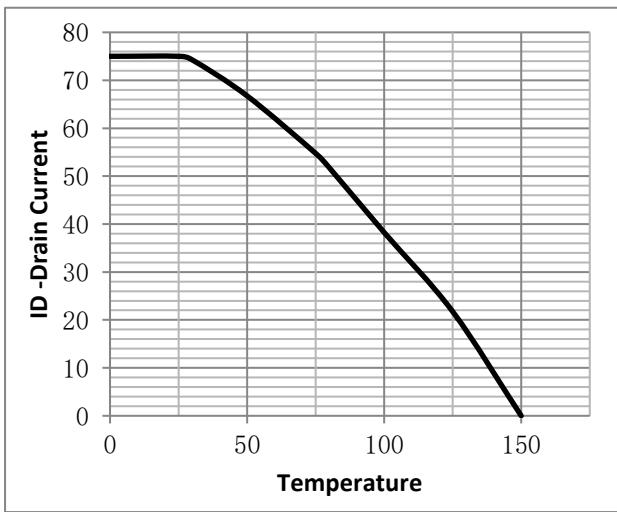


Fig.13 Gate Charge Measurement Circuit

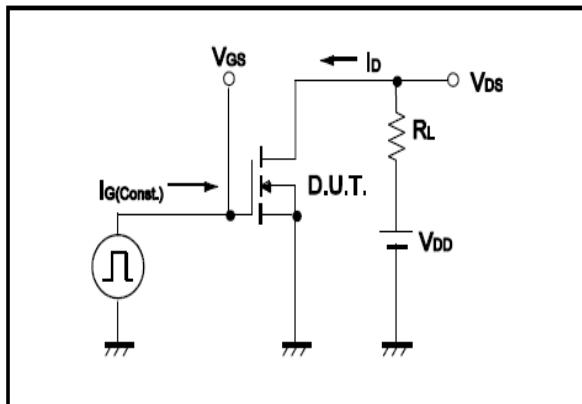


Fig.14 Gate Charge Waveform

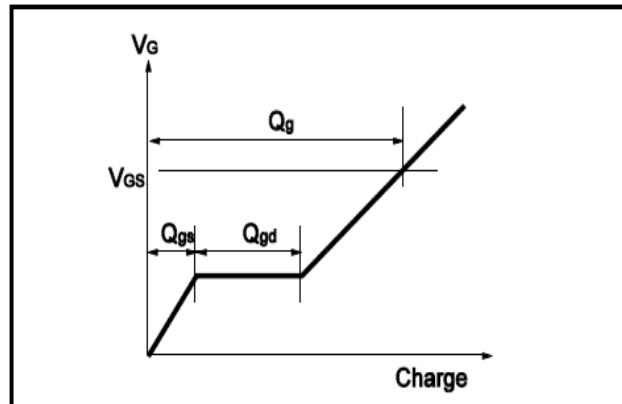


Fig.15 Switching Time Measurement Circuit

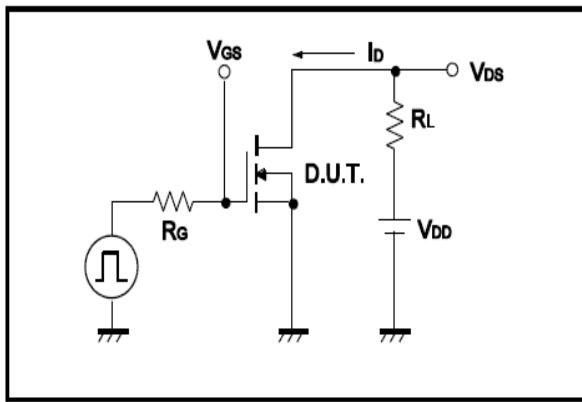


Fig.16 Switching Time Waveform

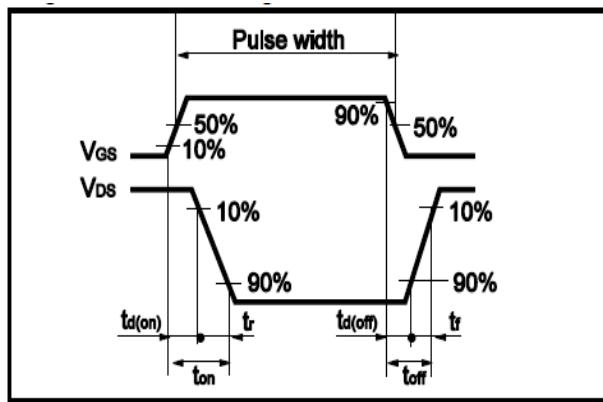


Fig.17 Avalanche Measurement Circuit

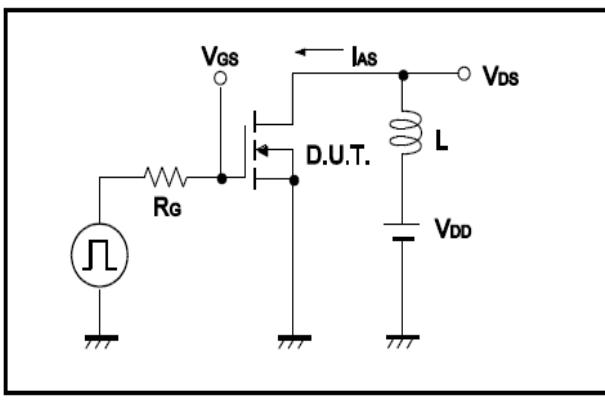
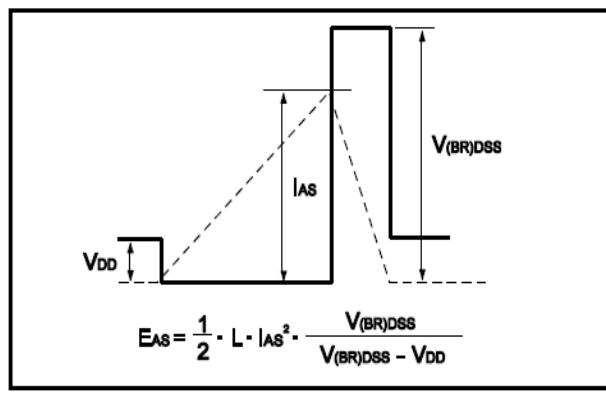


Fig.18 Avalanche Waveform

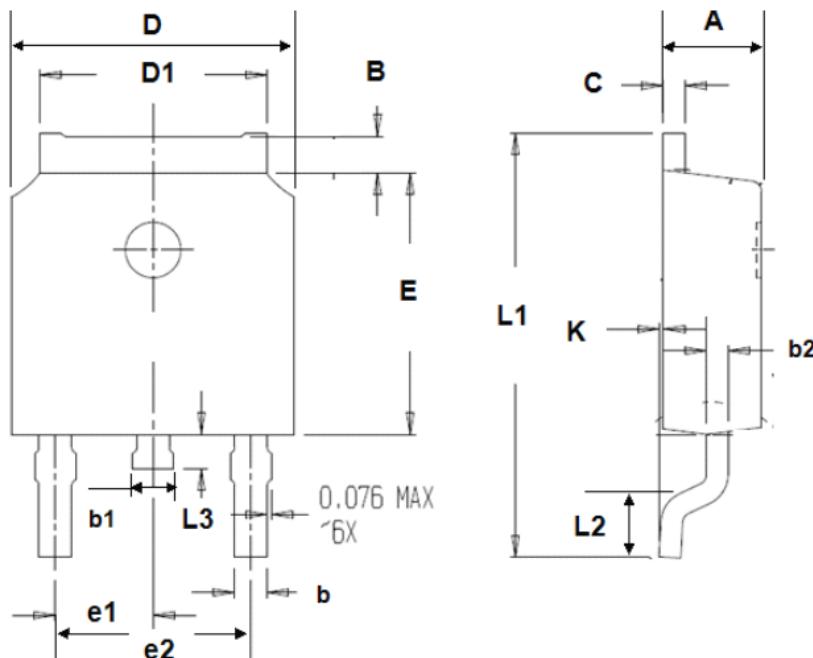




• Dimensions (TO-252)

Unit: mm

SYMBOL	min	max	SYMBOL	min	max
A	2.10	2.50	B	0.85	1.25
b	0.50	0.80	b1	0.50	0.90
b2	0.45	0.70	C	0.45	0.70
D	6.30	6.75	D1	5.10	5.50
E	5.30	6.30	e1	2.25	2.35
L1	9.20	10.60	e2	4.45	4.75
L2	0.90	1.75	L3	0.60	1.10
K	0.00	0.23			



Note:

- ① Pulse Test: Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$, Accumulation time ≤ 50 hours; For DC , the following test conditions can be passed: $VGS=+15V/-5V$, $Tj=175^{\circ}C$, $t=1000$ hours;
- ② Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate;
- ③ $Vgs \geq 4.5V$ is required for practical application.

Disclaimer

- Reproducing and modifying information of the document is prohibited without permission from ZMJ SEMICONDUCTORS CO.,LTD.
- ZMJ SEMICONDUCTORS CO.,LTD. reserves the rights to make changes of the content herein the document anytime without notification. Please refer to our website for the latest document.
- ZMJ SEMICONDUCTORS CO.,LTD. disclaims any and all liability arising out of the application or use of any product including damages incidentally and consequentially occurred.
- ZMJ SEMICONDUCTORS CO.,LTD. does not assume any and all implied warranties, including warranties of fitness for particular purpose, non-infringement and merchantability.
- Applications shown on the herein document are examples of standard use and operation. Customers are responsible in comprehending the suitable use in particular applications. ZMJ SEMICONDUCTORS CO.,LTD. makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.
- The products shown herein are not designed and authorized for equipments relating to human life and for any applications concerning life-saving or life-sustaining, such as medical instruments, aerospace machinery et cetera. Customers using or selling these products for use in such applications do so at their own risk and agree to fully indemnify ZMJ SEMICONDUCTORS CO.,LTD. for any damages resulting from such improper use or sale.
- Since ZMJ uses lot number as the tracking base, please provide the lot number for tracking when complaining.